

HYG110C03LR1D4

30V Complementary MOSFET

Feature

N- Channel

V_{ds} = 30V

29 A (V_{gs}= 10V)

9.0 mΩ (V_{gs}= 10V)

13.5 mΩ (V_{gs}= 4.5V)

P - Channel

V_{ds} = -30V

-17 A (V_{gs}= -10V)

21 mΩ (V_{gs}= -10V)

43 mΩ (V_{gs}= -4.5V)

- 100% Avalanche Tested
- Reliable and Rugged
- Halogen Free and Green Devices Available
(RoHS Compliant)

Pin Description

Applications

- Synchronous Rectifiers
- Wireless Power
- H-bridge Motor Drive

Ordering and Marking Information

HYG110C03LR1D4

Absolute Maximum Ratings

Symbol	Parameter	N- Channel	P- Channel	Unit
Common Ratings (T _c =25°C Unless Otherwise Noted)				

N-Mosfet Typical Operating Characteristics

Figure 1: Power Dissipation

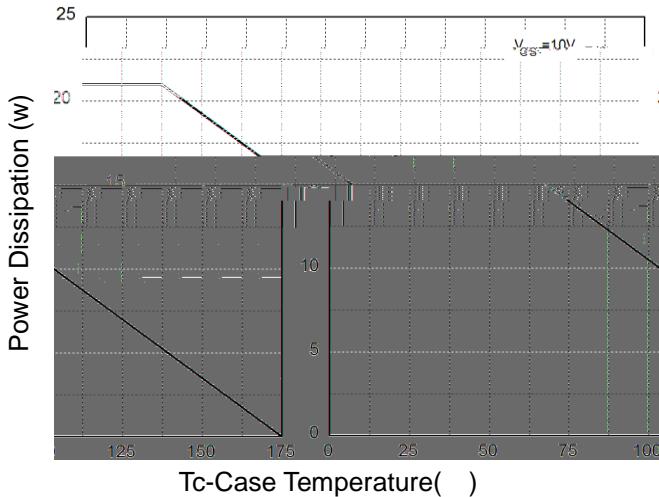


Figure 2: Drain Current

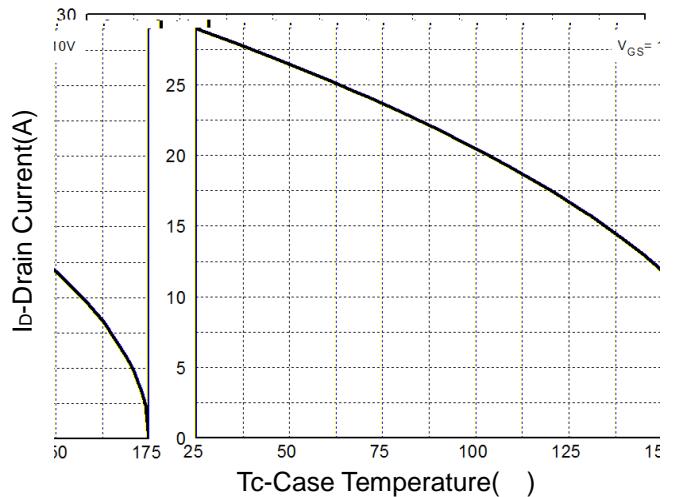


Figure 3: Safe Operation Area

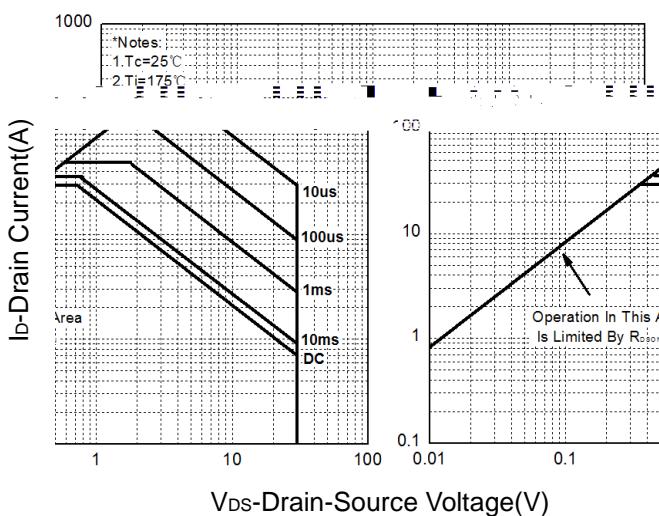


Figure 4: Thermal Transient Impedance

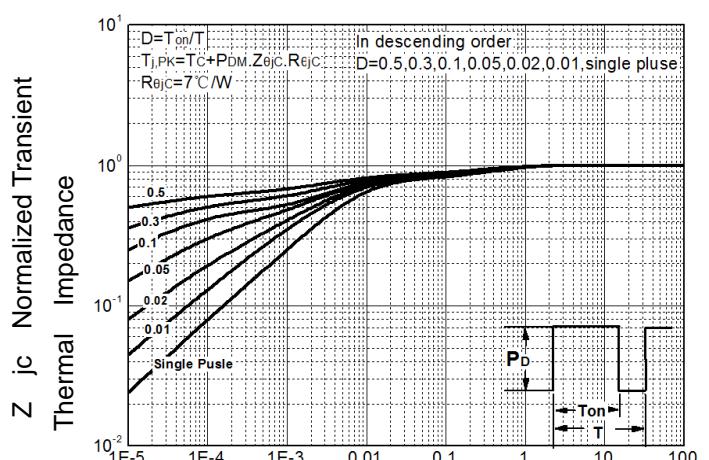


Figure 5: Output Characteristics

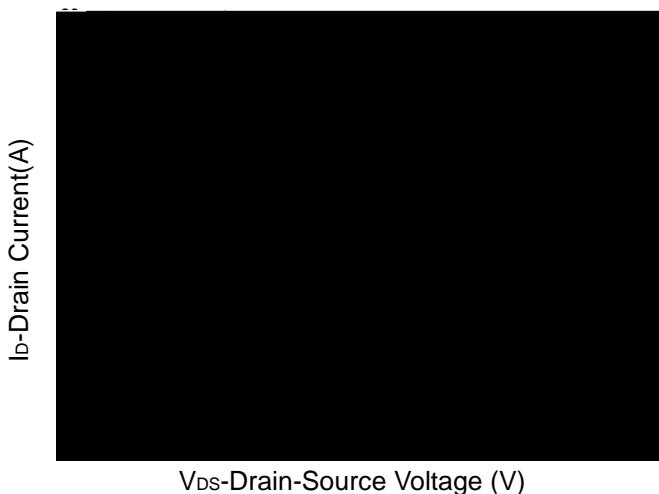
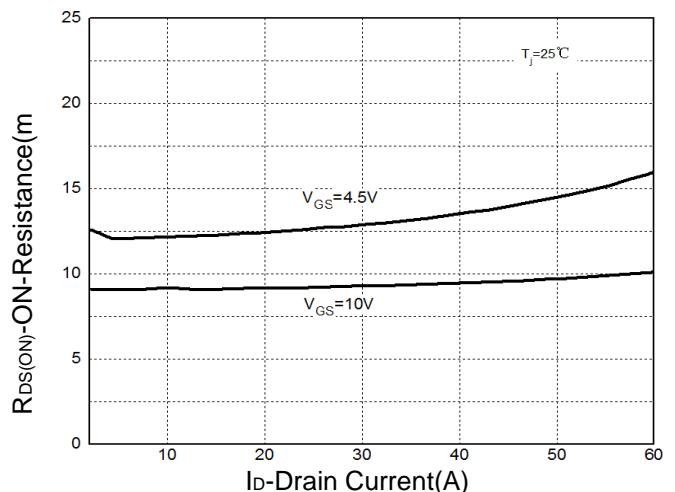


Figure 6: Drain-Source On Resistance



N-Mosfet Typical Operating Characteristics

Figure 7: On-Resistance vs. Temperature

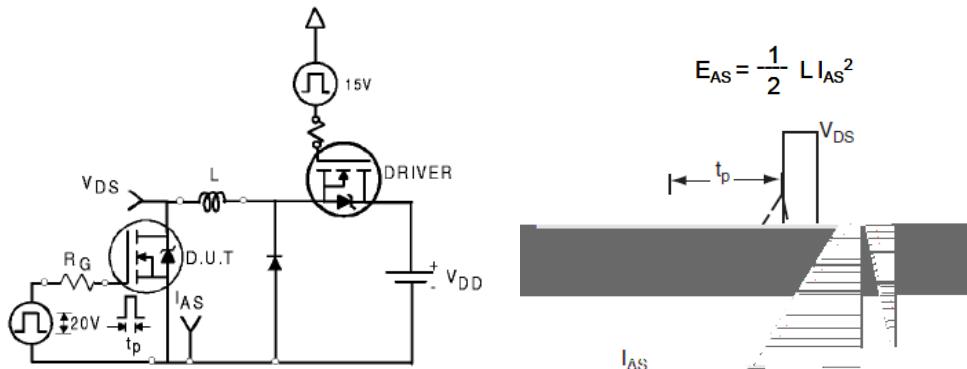
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Figure 8: Source-Drain Diode ForwardT_j-Junction Temperature ()V_{SD}-Source-Drain Voltage(V)**Figure 9: Capacitance Characteristics**

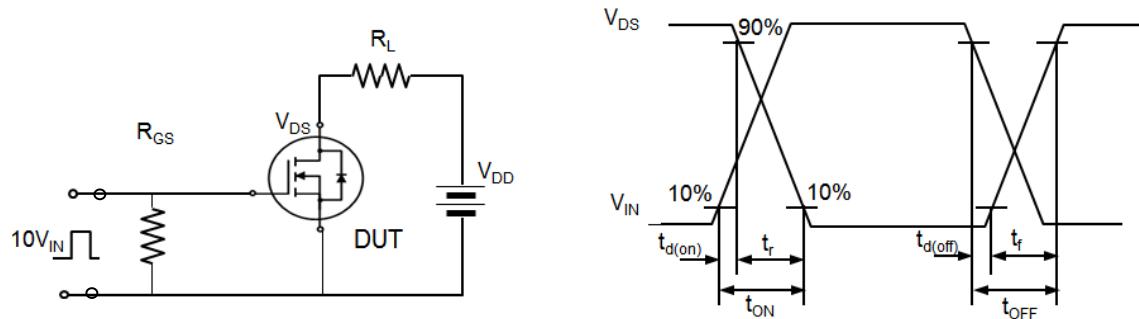
C-Capacitance(pF)

V_{DS}-Drain-Source Voltage (V)V_{Gs}-Gate-Source Voltage (V)**Figure 10: Gate Charge Characteristics**Q_G-Gate Charge (nC)

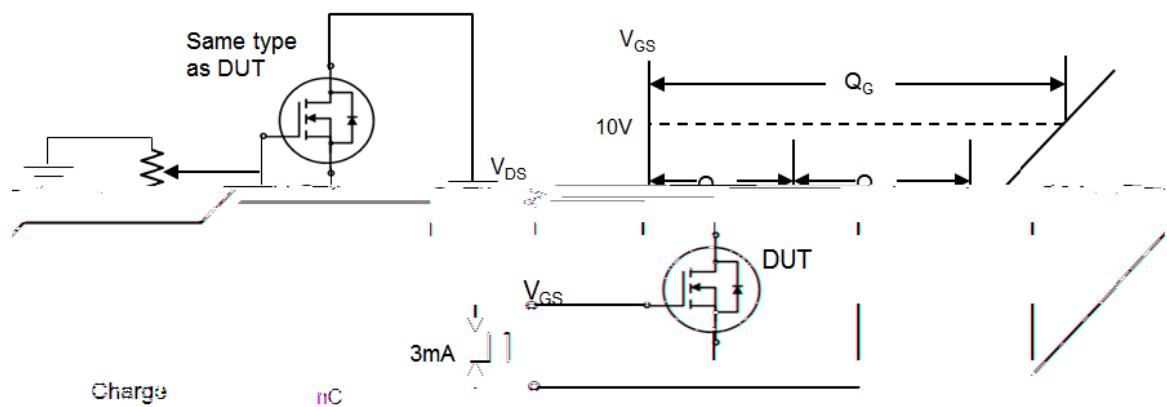
Avalanche Test Circuit



Switching Time Test Circuit



Gate Charge Test Circuit



HYG110C03LR1D4

P-Mosfet Electrical Characteristics ($T_c = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	HYG110C03LR1			Unit
			Min	Typ.	Max	
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=-250 \text{ A}$	-30	-		V
I_{DSS}	Drain-to-Source Leakage Current	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}$		-	-1	A
			$T_J=125^\circ\text{C}$	-	-50	A
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{DS}}=-250 \text{ A}$	-1	-1.9	-3	V
I_{GSS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$R_{\text{DS}(\text{ON})^*}$	Drain-Source On-State Resistance	$V_{\text{GS}}=-10\text{V}, I_{\text{DS}}=-6\text{A}$	-	21	26	m
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{DS}}=-4\text{A}$		43	55	
Diode Characteristics						
V_{SD}^*	Diode Forward Voltage	$I_{\text{SD}}=-1\text{A}, V_{\text{GS}}=0\text{V}$	-	-0.76	-1.0	V
t_{rr}	Reverse Recovery Time	$I_{\text{SD}}=-12\text{A}, dI_{\text{SD}}/dt=100\text{A}/\text{s}$	-	10.0	-	ns
Q_{rr}	Reverse Recovery Charge		-	7.1	-	nC

P-Mosfet Electrical Characteristics (Cont.) ($T_c = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	HYG110C03LR1		Unit
			Min	Typ.	

P-Mosfet Typical Operating Characteristics

Figure 1: Power Dissipation

Tc-Case Temperature(°C)

Figure 2: Drain Current

Tc-Case Temperature(°C)

Figure 3: Safe Operation Area

-V

Figure 4: Thermal Transient Impedance

P-Mosfet Typical Operating Characteristics

Figure 7: On-Resistance vs. Temperature

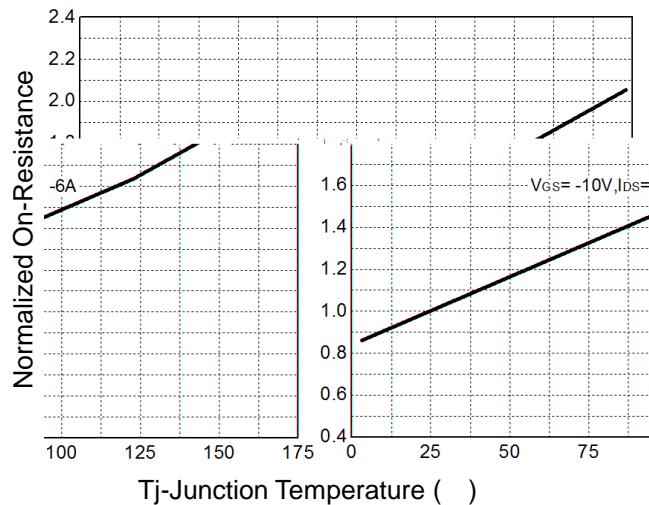


Figure 8: Source-Drain Diode Forward

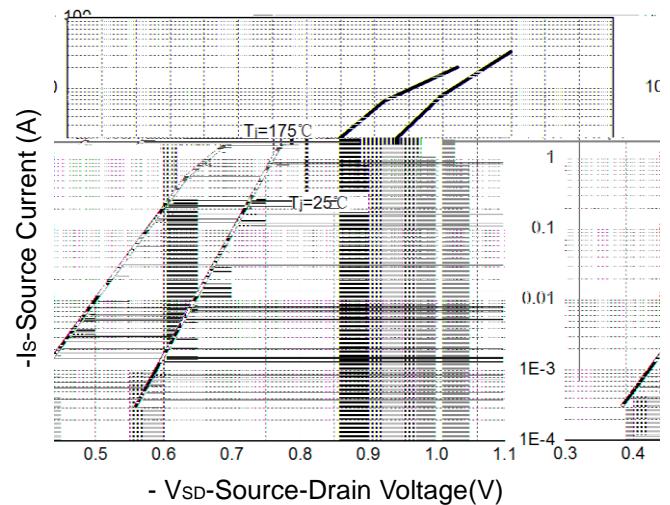


Figure 9: Capacitance Characteristics

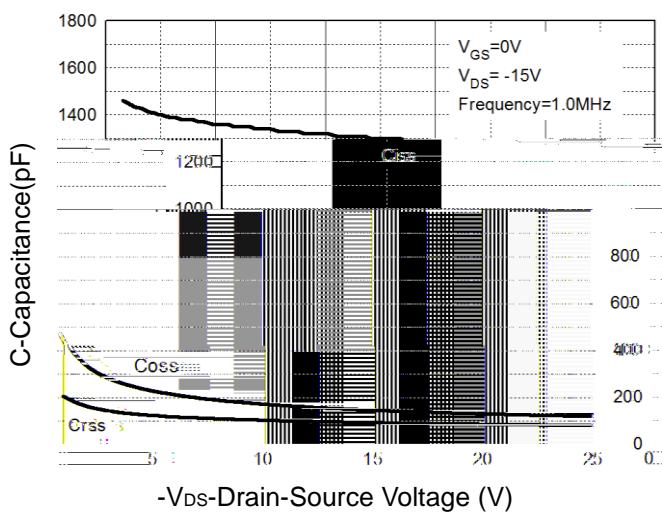
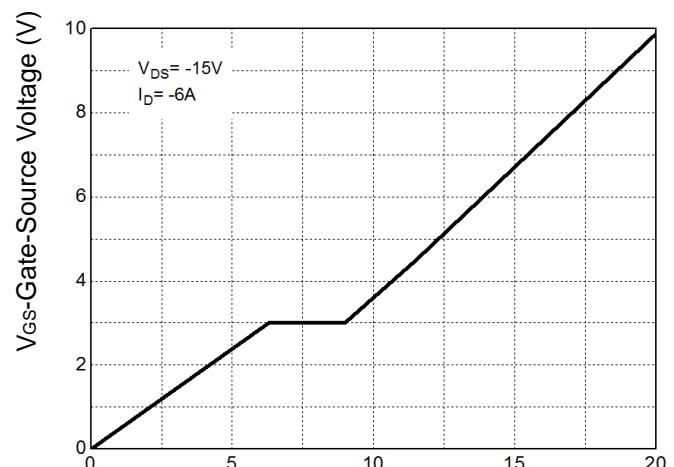
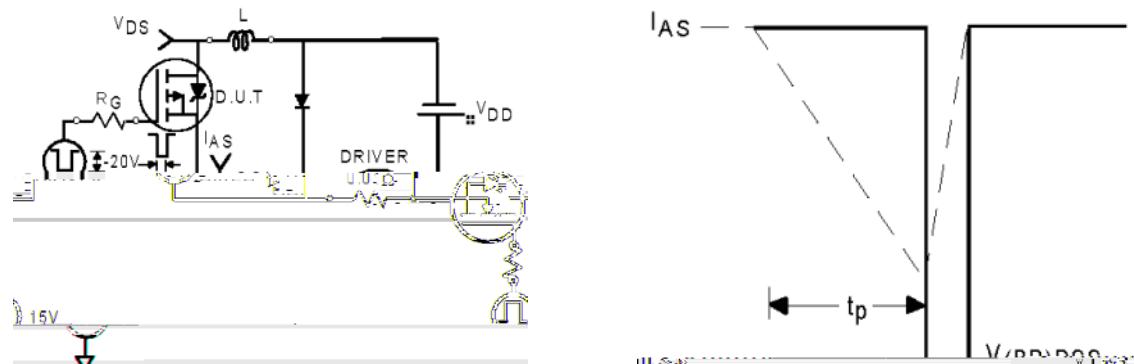


Figure 10: Gate Charge Characteristics

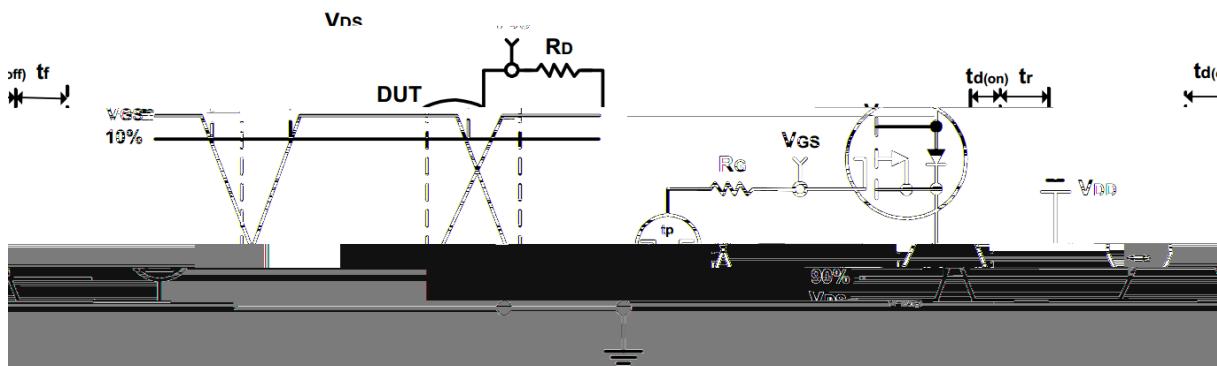


HYG110C03LR1D4

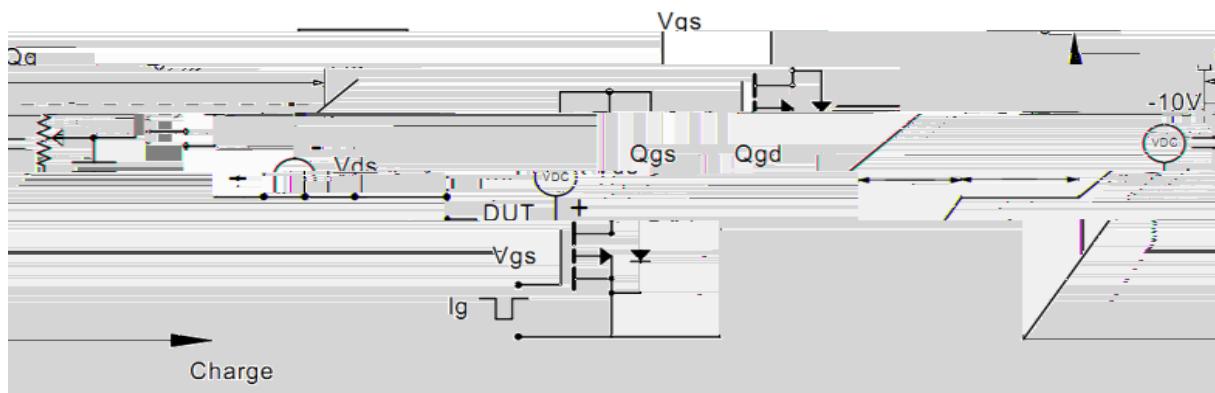
Avalanche Test Circuit



Switching Time Test Circuit



Gate Charge Test Circuit



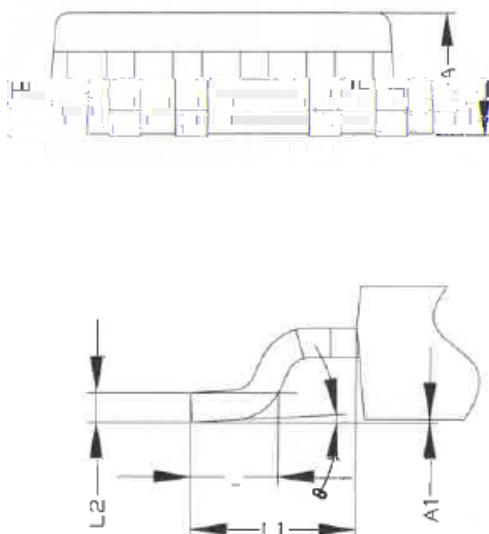
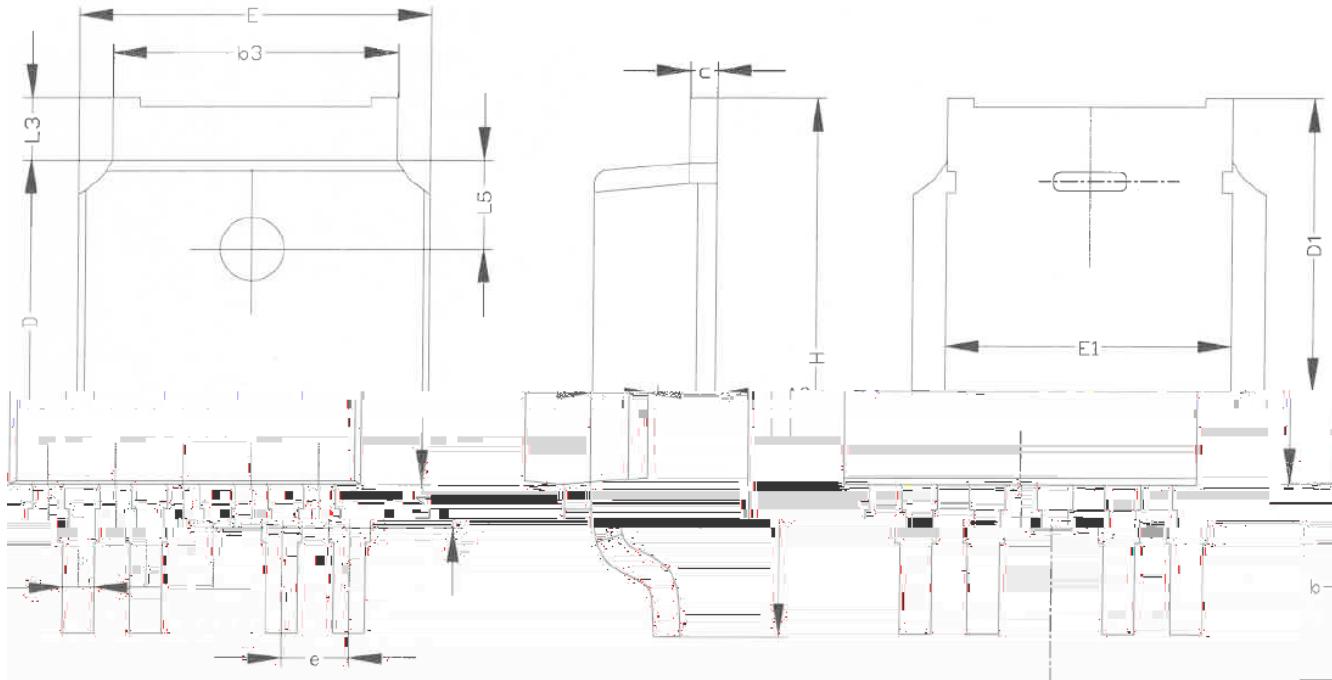
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Device Per Unit

Package Type	Unit	Quantity
TO-252-4L	Reel	2500
TO-252-4L	Tube	75

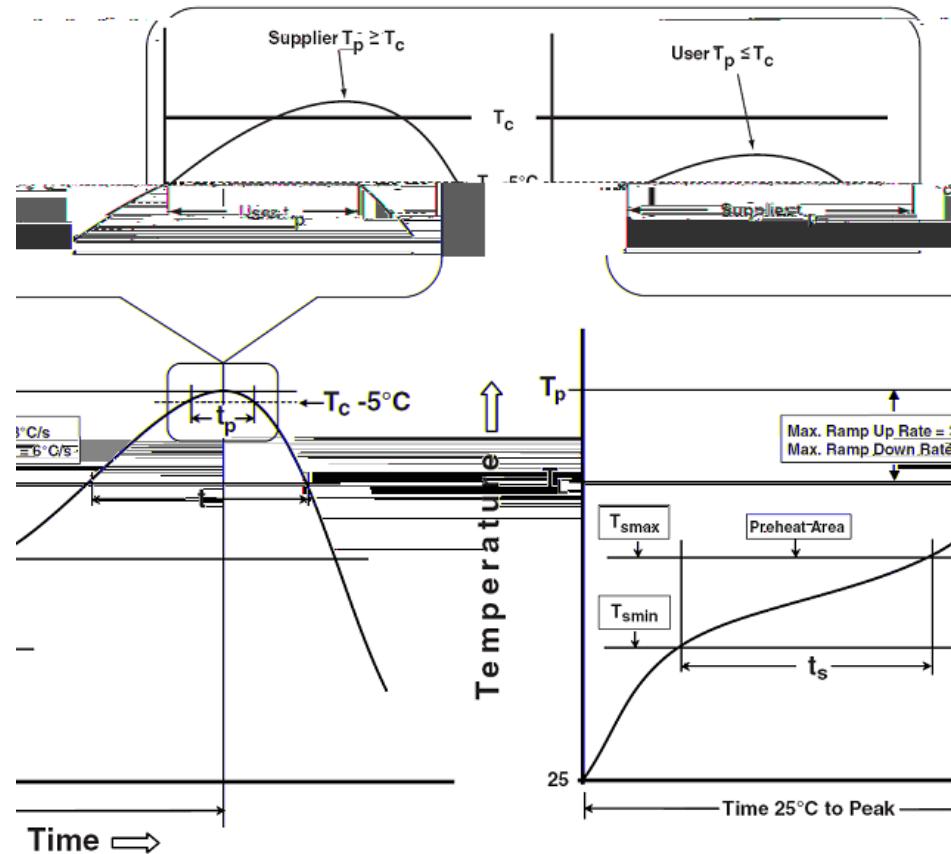
Package Information

TO-252-4L



SYMBOL	COMMON DIMENSIONS			
	mm	MIN	NOM	MAX
A	2.20	2.30	2.38	
A1	0.00	-	0.20	
A2	0.97	1.07	1.17	
b	0.55	0.62	0.70	
b3	5.20	5.33	5.46	
c	0.43	0.53	0.61	
D	5.98	6.10	6.22	
D1	5.30REF			
E	6.40	6.60	6.73	
E1	5.10	-	-	
e	1.27 BSC			
H	9.40	10.10	10.50	
L	1.38	1.50	1.75	
L1	2.90REF			
L2	0.51BSC			
L3	0.88	-	1.28	
L4	0.50	-	1.00	
L5	1.65	1.80	1.95	
	0°	-	8°	

Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak		
Temperature min (T_{smin})	100 °C	150 °C
Temperature max (T_{smax})	150 °C	200 °C
Time (T_{smin} to T_{smax}) (t_s)	60-120 seconds	60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L)	183 °C	217 °C
Time at liquidous (t_L)	60-150 seconds	60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.

*Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum.

** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.

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Table 1.SnPb Eutectic Process Classification Temperatures (Tc)

Package Thickness	Volume mm ³	Volume mm ³
	<350	350
2.5 mm	235 °C	220 °C
	220 °C	220 °C

Table 2.Pb-free Process Classification Temperatures (Tc)

Package Thickness	Volume mm ³	Volume mm ³	Volume mm ³
	<350	350-2000	2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm 2.5 mm	260 °C	250 °C	245 °C
2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	